

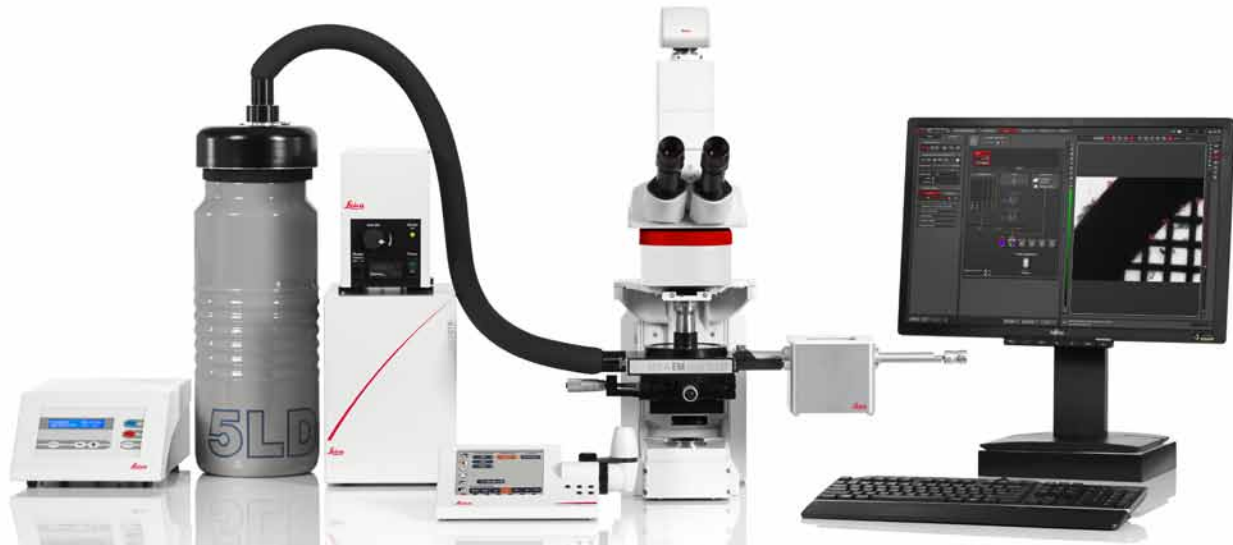
Leica LAS X Cryo CLEM Software Increase Sample Throughput with Lightning Speed Correlation Process

Connect your Widefield System with the Electron Microscope for High-Precision Correlative Imaging using the software module Leica LAS X Cryo CLEM

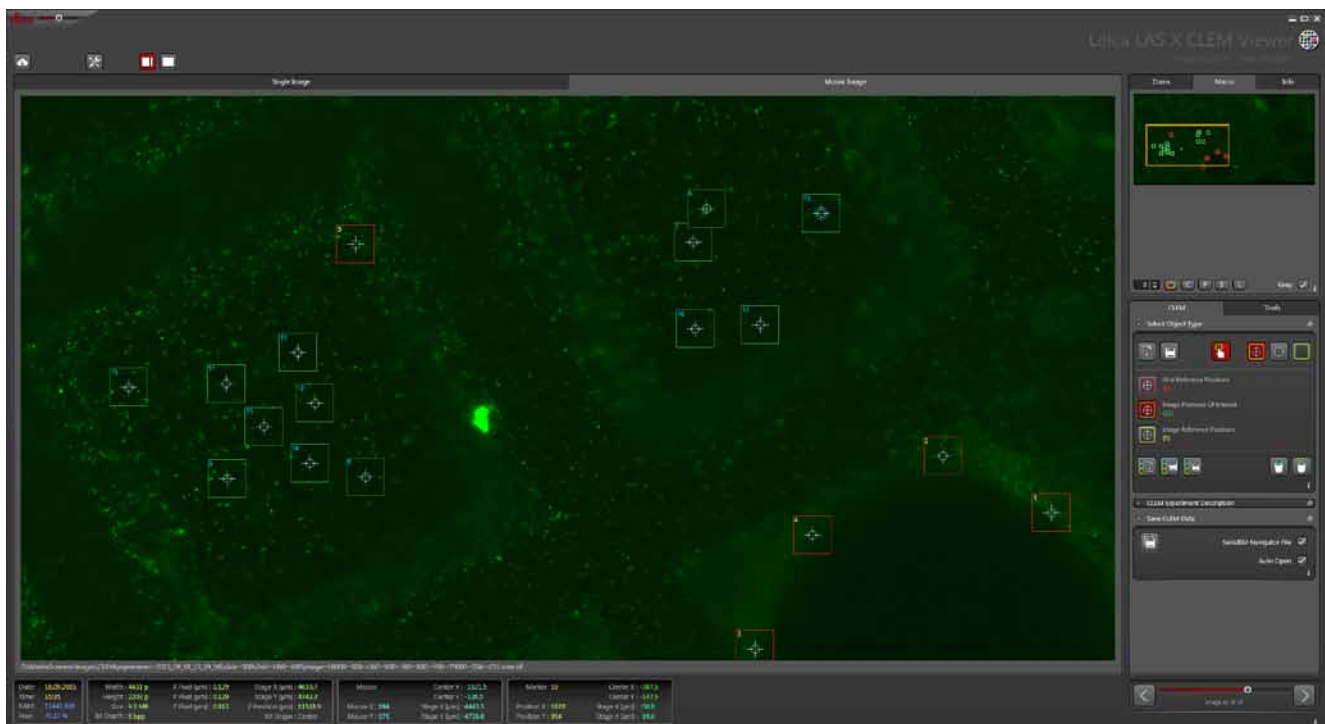
- Precise localization: Automatically scan large areas under the light microscope. Precisely define your object coordinates in the high resolution overview scan.
- Compatible: Transfer widefield coordinates to SerialEM software and correlate with any electron microscope connected to SerialEM.
- Efficient: "The automated acquisition and coordinate transfer capabilities introduced to LAS X have significantly increased the throughput of our cryo CLEM experiments," Martin Schorb, EMBL, Heidelberg, Germany.

Image above: Correlation of electron microscope and fluorescence images of grid squares in SerialEM.
Courtesy of John Briggs and Martin Schorb, EMBL, Heidelberg, Germany

Benefit from the efficiency and precision of the complete workflow: Leica Microsystems' hardware and software support the whole process from sample preparation to image acquisition and transfer of coordinates.



The Leica EM Cryo CLEM system: After sample preparation the specimen is transferred to the fluorescence microscope. LAS X Cryo CLEM software automatically scans the sample and generates a high resolution overview scan.



Fast and precise location of points of interest can be done offline in the Leica CLEM Viewer. The coordinates are then transferred to SerialEM.